

Document S1 (Measurement of Type II columnar APD widths)

Supplementary material for:

Various antiphase domains in garnet-hosted omphacite in low temperature eclogite: A FIB–TEM study on heterogeneous ordering processes

Ryo Fukushima¹, Tatsuki Tsujimori^{1,2}, Nobuyoshi Miyajima³

¹ Graduate School of Science, Tohoku University, Sendai 980-8578, Japan

² Center for Northeast Asian Studies, Tohoku University, Sendai 980-8576, Japan

³ Bayerisches Geoinstitut, Universität Bayreuth, 95440 Bayreuth, Germany

Corresponding author: Ryo Fukushima

E-mail address: ryo.fukushima.p7@dc.tohoku.ac.jp

Address: Graduate School of Science, Tohoku University, 41 Kawauchi, Aoba, Sendai 980-8578, Japan

Phone/Fax: +81-22-795-6236

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Measurement of Type II columnar APD widths

To measure widths of the elongated APDs perpendicular to garnet–omphacite interfaces (Type II columnar APDs), we binarized digital images similarly to the case of measurement of equiaxed APD sizes. Figure S1 shows measured segments and histograms of the measured APD widths.

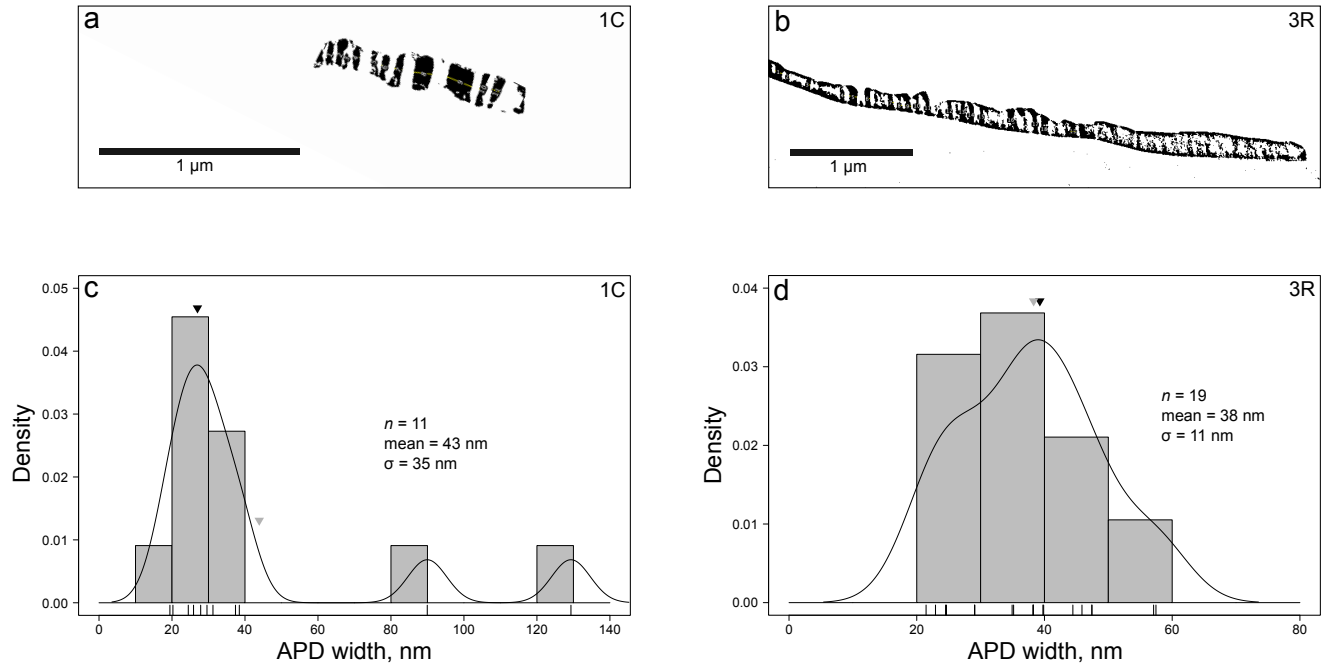


Figure S1. Measurement of widths of the Type II APDs: **a** binarized image of 1C; **b** a binarized image of 3R; **c** histogram of the measured data in 1C; **d** histogram of the measured data in 3R. Results of the kernel density estimates are also shown. Band widths are set to 5.297 nm (1C) and 5.351 nm (3R). The black and gray triangles show the mode and mean values, respectively.